

Abstract Submitted  
for the MAR10 Meeting of  
The American Physical Society

**Depth resolved x-ray excited optical luminescence from SrTiO<sub>3</sub>**<sup>1</sup>

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<sup>1</sup>This work was performed at the Advanced Photon Source and was supported by the U.S. Department of Energy, Office of Science, Office of Basic Energy Sciences under Contract No. DE-AC02-06CH11357.

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Date submitted: 08 Jan 2010

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